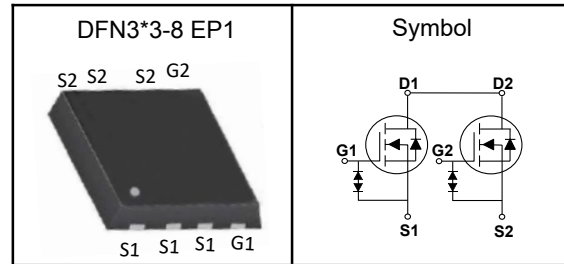


Common-Drain Dual N-Channel Enhancement Mode MOSFET
Features

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant
- 100% Avalanche Tested

Applications

- Power Management in Desktop Computer
- DC/DC Converters

Pin Description


V_{DSS}	18	V
$R_{DS(ON)-Typ}$	3.5	m Ω
I_D	55	A

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$, Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit	
V_{DSS}	Drain-Source Voltage	18	V	
V_{GSS}	Gate-Source Voltage	± 10	V	
T_J	Maximum Junction Temperature	-55 to 150	$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$	
E_{AS}	Single Pulse Avalanche Energy	100	mJ	
$I_{DM}^{①}$	Pulse Drain Current Tested	165	A	
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	55	A
	Continuous Drain Current	$T_C=100^\circ\text{C}$	24	A
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	35	W

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	78	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3.5	$^\circ\text{C}/\text{W}$

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C .

Note ③ : Surface Mounted on 1in^2 FR-4 board with 1oz.



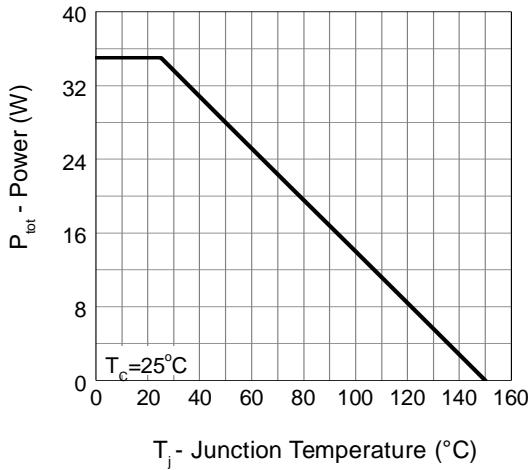
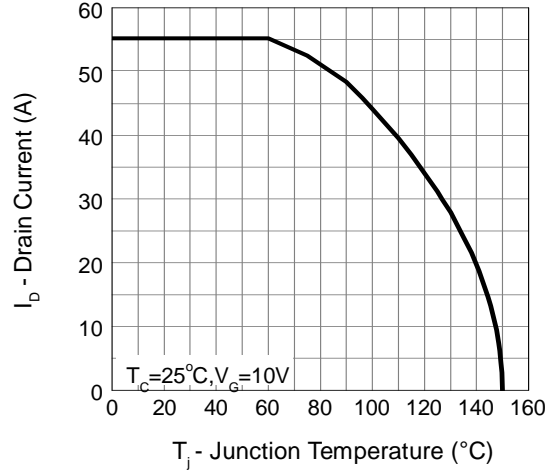
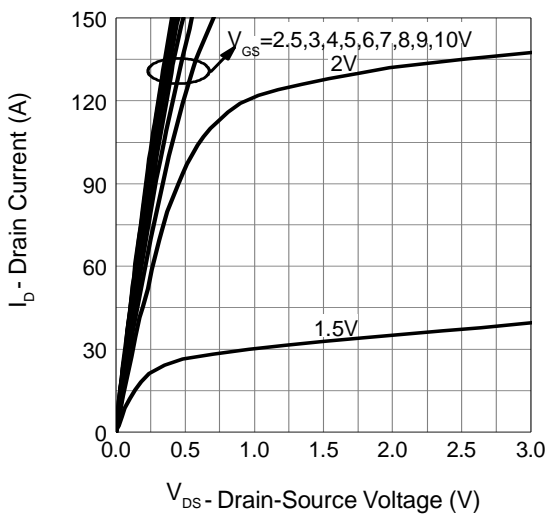
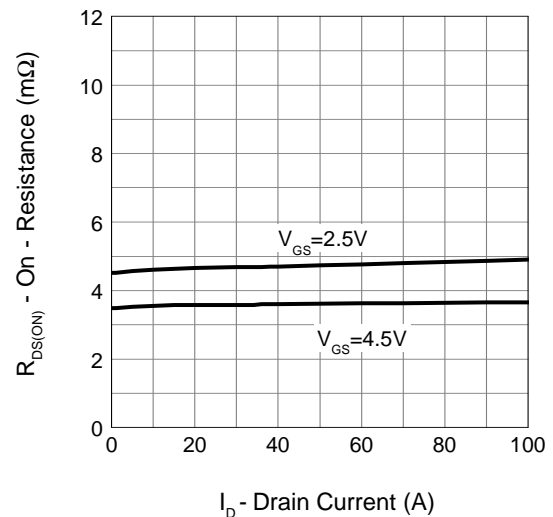
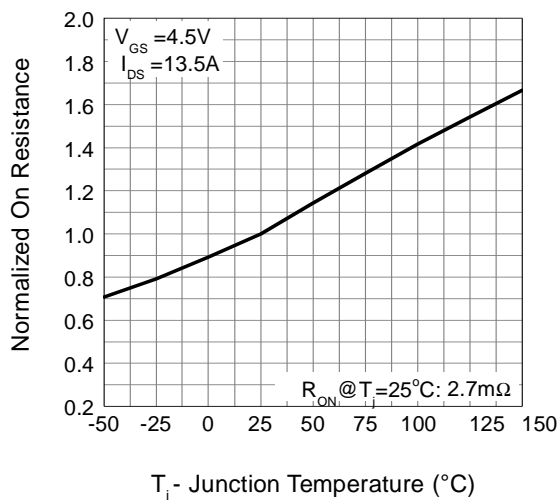
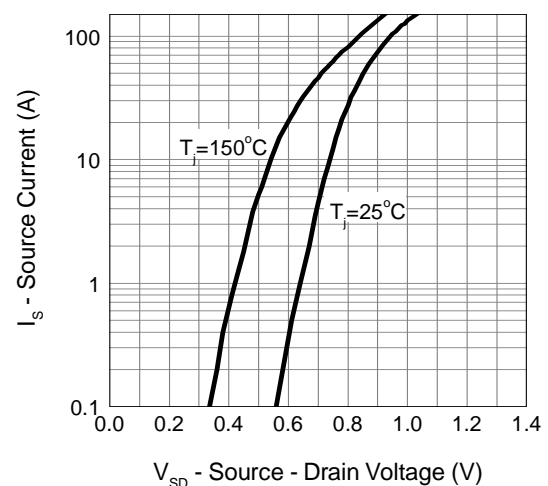
Common-Drain Dual N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^{\circ}\text{C}$, Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	18	---	---	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=14.4V, V_{GS}=0V$	---	---	1	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	---	1.0	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 10V, V_{DS}=0V$	---	---	± 10	μA
$R_{DS(on)}$	Drain-Source On-state Resistance	$V_{GS}=4.5V, I_D=13.5A$	---	3.5	5.0	m Ω
		$V_{GS}=2.5V, I_D=10A$	---	4.5	6.0	
Dynamic Characteristics ^⑤						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=10V, \text{Freq.}=1.0\text{MHz}$	---	3775	---	pF
C_{oss}	Output Capacitance		---	730	---	
C_{riss}	Reverse Transfer Capacitance		---	525	---	
$T_{d(on)}$	Turn-on Delay Time	$V_{GS}=10V, V_{DD}=10V, I_D=1A, R_G=6\Omega$	---	14	---	nS
T_r	Turn-on Rise Time		---	14.5	---	
$T_{d(off)}$	Turn-off Delay Time		---	130	---	
T_f	Turn-off Fall Time		---	70	---	
Q_g	Total Gate Charge	$V_{GS}=4.5V, V_{DD}=10V, I_D=13.5A$	---	35	---	nC
Q_{gs}	Gate-Source Charge		---	4.7	---	
Q_{gd}	Gate-Drain Charge		---	11.5	---	
Source-Drain Characteristics						
V_{SD}	Diode Forward Voltage	$I_S=2A, V_{GS}=0V$	---	---	1.1	V
t_{rr}	Reverse recovery time	$I_F=13.5A, diF/dt=100A/\mu s$	---	18	---	ns
Q_{rr}	Reverse recovery charge		---	6.2	---	nC

Note ④: Pulse test (pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$).

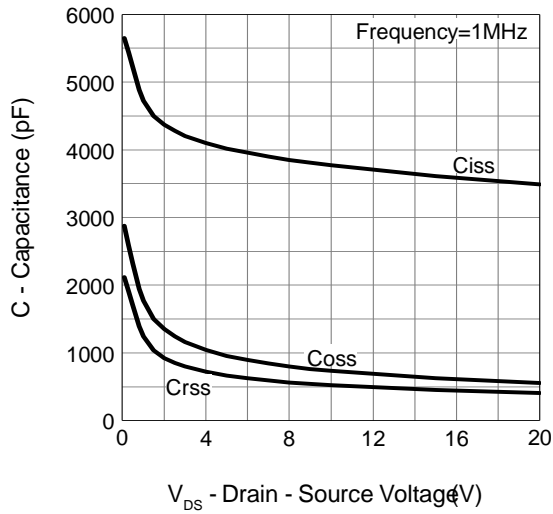
Note ⑤: Guaranteed by design, not subject to production testing.

Common-Drain Dual N-Channel Enhancement Mode MOSFET
Typical Characteristics
Power Dissipation

Drain Current

Output Characteristics

Drain-Source On Resistance

Drain-Source On Resistance

Source-Drain Diode Forward


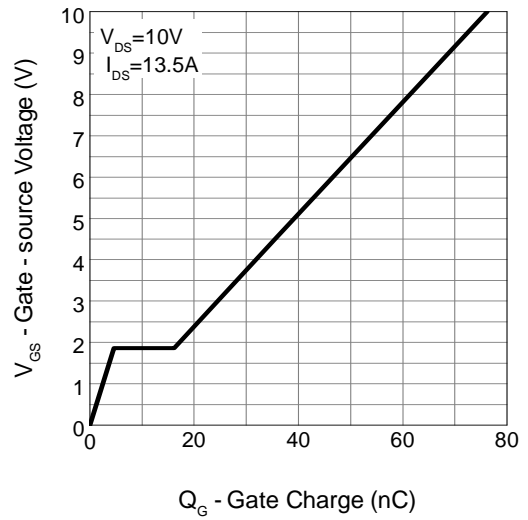


Common-Drain Dual N-Channel Enhancement Mode MOSFET

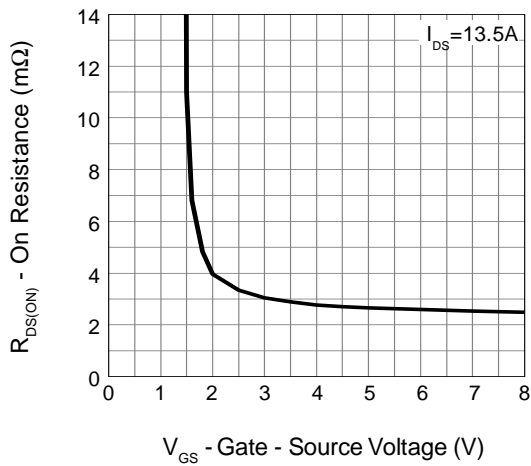
Capacitance



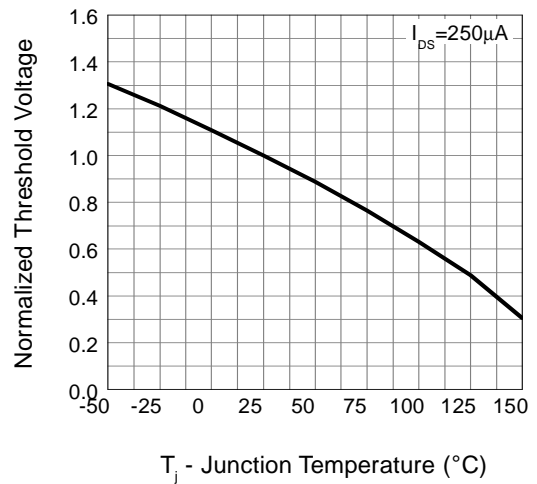
Gate Charge



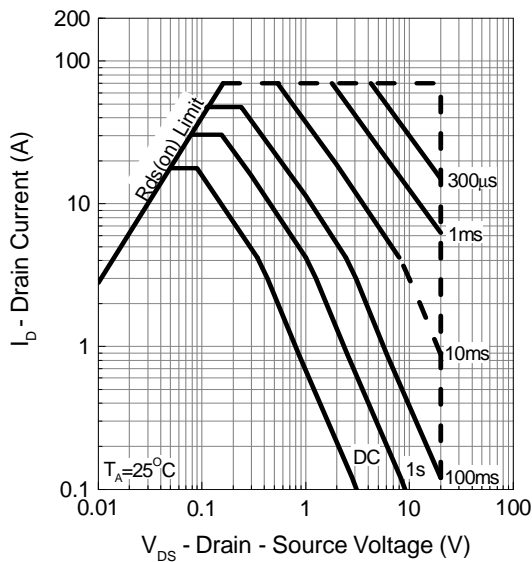
Gate-Source On Resistance



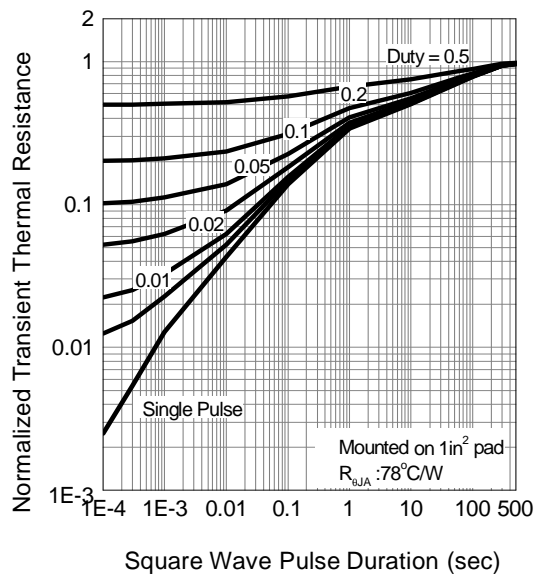
Gate Threshold Voltage

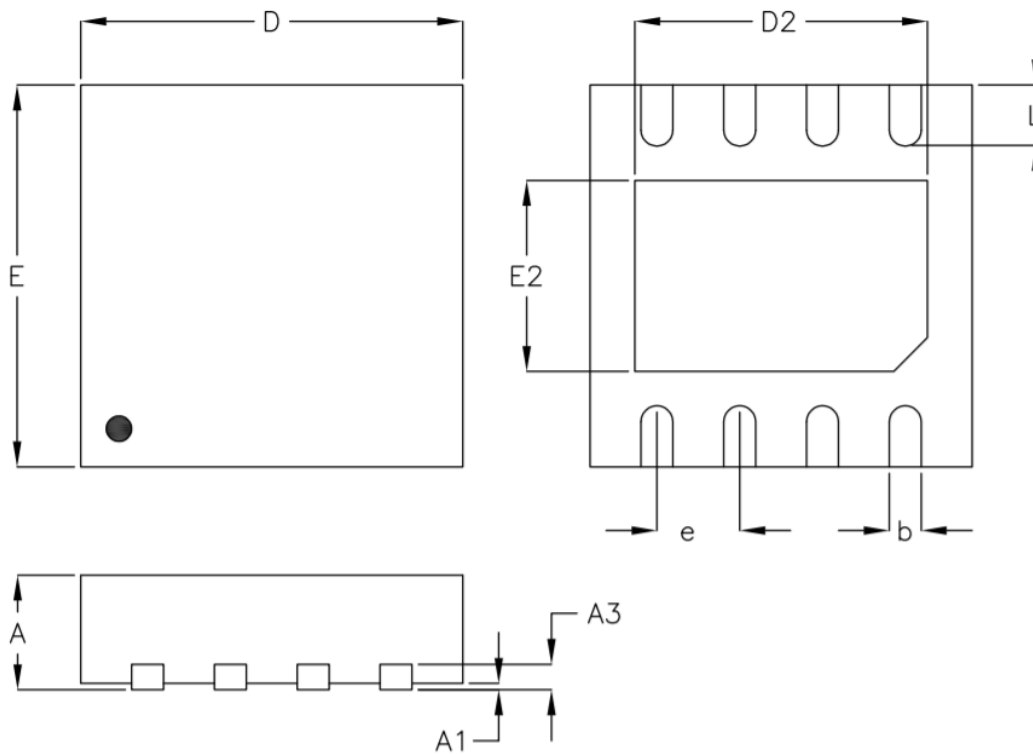


Safe Operation Area



Thermal Transient Impedance



Common-Drain Dual N-Channel Enhancement Mode MOSFET
DFN3*3-8 EP1 Package Outline Data


Symbol	Dimensions (unit:mm)			Symbol	Dimensions (unit:mm)		
	Min	Typ	Max		Min	Typ	Max
A	0.70	0.75	0.80	D2	2.25	2.40	2.55
A1	0.00		0.05	E	2.90	3.00	3.10
A3	0.18	0.20	0.25	E2	1.50	1.65	1.75
b	0.25	0.30	0.35	e	0.65 BSC		
D	2.90	3.00	3.10	L	0.30	0.40	0.50